

<b>Notice of References Cited</b>	Application/Control No. 10/020,825	Applicant(s)/Patent Under Reexamination CRAIG ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,182,120	01-1980	Niebylski, Leonard M.	422/176
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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